

Report No. MCR-22-0779

Date: Nov./25/2022

# RENESAS SEMICONDUCTOR RELIABILITY REPORT

SERIES : RL78/D1A

DEVICE : R5F10zGxCyFB/R5F10zGxCyXXXFB

(z=C/D,x=B/C/D/E,y=J/L)

APPLICATION: Automobile

Quality Assurance Div. Renesas Electronics Corporation

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#### $Q100\ Qualification\ Test\ Results\ for\ R5F10zGxCyFB/R5F10zGxCyXXXFB(z=C/D,x=B/C/D/E,y=J/L)$

[Note: Basically qualification tests were performed using a representative product with the same wafer process and the same package structure.]

Test	#	Reference	Test Conditions			S.S.	Total	Results	Comments:
			TEST GRO	OUP A – ACCELERAT	ED ENVIR	ONMENT S	<u> </u> STRESS TE	(Fail of Total)	(N/A =Not Applicable)
PC	A1	JESD22 A113 J-STD-020	Preconditioning: (Test @ Rm)			Min.MSL=3			-
THB <del>or</del> <del>HAST</del>	A2	JESD22 A101	Temperature Humidity Bias: (Test @ Rm/Ho Ta=85°C, RH=85%, 1000hrs	ot)	3	77	231	0 of 231	-
AC or UHST or TH	A3	JESD22 A118	Unbiased Highly Accelerated Stree Test: (Test @ Rm) 110°C, 85% RH, 264h			77	231	0 of 231	-
TC	A4	JESD22 A104	Temperature Cycle: (Test @ Hot) Ta=-65°C to 150°C, 500cyc			77	231	0 of 231 0 Fails after TC (WBP)	-
PTC	A5	JESD22 A105	Power Temperature Cycle: (Test @ Rm/Hot)	-	-	-	-	N/A	
HTSL	A6	JESD22 A103	High Temperature Storage Life: (Test @ Rm Ta=150°C, 1000hrs	/Hot)	1	45	45	0 of 45	-
			TEST GRO	OUP B – ACCELERAT	ED LIFET	IME SIMUI	LATION TI	ESTS	
HTOL	В1	JESD22 A108	High Temp Operating Life: (Test @ Rm/Col Ta=125°C, 1000hrs	d/Hot)	3	77	231	0 of 231	-
ELFR	В2	AEC-Q100-008	Early Life Failure Rate: (Test @ Rm/Hot) Ta=125°C, 48hrs	3	800	2400	0 of 2400	-	
EDR	В3	AEC-Q100-005	For HTOL NVM Endurance & Data Retention Test:		3	77	231	0 of 231	-
LDR		7100-003	(Test @ Rm/Hot)	For HTSL	1	45	45	0 of 45	-

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Page 3 of 8 AEC-Q100-REV H-QTR

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Test	#	Reference	Test Conditions		S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP C - PACKAG	E ASSEMB	LY INTEG	RITY TEST	'S	
WBS	C1	AEC-Q100-001 AEC-Q003	Wire Bond Shear Test: (Cpk > 1.67)	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Cpk>1.67
WBP	C2	Mil-STD-883 Method 2011 AEC-Q003	Wire Bond Pull: (Cpk > 1.67); Each bonder used	30 bonds	5 parts Min.	30 bonds	0 of 30bonds	Cpk>1.67
SD	СЗ	JESD22 B102 JSTD-002D	Solderability: (>95% coverage) 8 hr steam aging prior to testing	1	15	15	0 of 15	
PD	C4	JESD22 B100, JESD22 B108 AEC-Q003	Physical Dimensions: (Cpk > 1.67)	3	10	30	0 of 30	Cpk>1.67
SBS	C5	AEC-Q100-010 AEC-Q003	Solder Ball Shear: (Cpk > 1.67); 5 balls from min. of 10 devices	-	-	-	-	N/A
LI	С6	JESD22 B105	Lead Integrity: (No lead cracking or breaking); Through-hole only; 10 leads from each of 5 devices	-	-	-	-	N/A
			TEST GROUP D – DIE FAB	RICATION	RELIABII	ITY TESTS	8	
EM	D1	JESD61	Electromigration:	-	-	-	Pass	Confirmed by process TEG
TDDB	D2	JESD35	Time Dependant Dielectric Breakdown:	-	-	-	Pass	Confirmed by process TEG
HCI	D3	JESD60 & 28	Hot Carrier Injection:	-	-	-	Pass	Confirmed by process TEG
NBTI	D4	JESD90	Negative Bias Temperature Instability:	-	-	-	Pass	Confirmed by process TEG
SM	D5	JESD61,87 & 202	Stress Migration:	-	-	-	Pass	Confirmed by process TEG

Page 4 of 8 AEC-Q100-REV H-QTR

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)
			TEST GROUP E- ELE	CTRICAL	VERIFICA	TION		
TEST	E1	User/Supplier Specification	Pre and Post Stress Electrical Test:	All A		All	0 of All	-
НВМ	E2	AEC-Q100-002	Electrostatic Discharge, Human Body Model: (Test @ Rm/Hot); (2KV HBM / Class 2 or better)	1	3	3	0 of 3 ESD Level= HBM:2	HBM>2KV
CDM	E3	AEC-Q100-011	Electrostatic Discharge, Charged Device Model: (Test @ Rm/Hot); (750V corner leads, 500V all other leads / Class C4B or better)	1	3	3	0 of 3 ESD Level= CDM:C4B	Corner leads: 750V Pass All other leads:500V Pass
LU	E4	AEC-Q100-004	Latch-Up: (Test @ Rm/Hot)	1	6	6	0 of 6	-
ED	E5	AEC-Q100-009 AEC-Q003	Electrical Distributions: (Test @ Rm/Hot/Cold) (where applicable, Cpk>1.67)	3	30	90	Cpk>1.67	-
FG	E6	AEC-Q100-007	Fault Grading:	-	-	-	>98%	-
CHAR	E7	AEC-Q003	Characterization: (Test @ Rm/Hot/Cold)	-	-	-	Pass	According to Renesas standard procedure
EMC	E9	SAE J1752/3	Electromagnetic Compatibility (Radiated Emissions)	1	1	1	0 of 1	-
SC	E10	AEC Q100-012	Short Circuit Characterization	-	-	-	-	N/A
SER	E11	JESD89-1 JESD89-2 JESD89-3	Soft Error Rate	1	3	3	Pass	-
LF	E12	AEC-Q005	Lead (Pb) Free: (see AEC-Q005)	-	-	-	Pass	Solderability: See SD (C3) result. Solder heat resistance: N/A (Wave Solder is Not recommended.) Whisker: Performed on product TEG with test method based on JESD201.

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Page 5 of 8 AEC-Q100-REV H-QTR

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Test	#	Reference	Test Conditions	Lots	S.S.	Total	Results (Fail of Total)	Comments: (N/A =Not Applicable)			
			TEST GROUP F – DE	FECT SCR	EENING T	ESTS					
PAT	F1	AEC-Q001	Process Average Testing: (see AEC-Q001)	All	All	All	Reject units outside PAT limits	Apply to mass production according to Renesas standard procedure			
SBA	F2	AEC-Q002	Statistical Bin/Yield Analysis: (see AEC-Q002)	All	All	All	Reject units outside criteria	Apply to mass production according to Renesas standard procedure			
	TEST GROUP G - CAVITY PACKAGE INTEGRITY TESTS (for Ceramic Package testing only)										
MS	G1	JESD22 B104	Mechanical Shock: (Test @ Rm)	-	-	-	-	N/A			
VFV	G2	JESD22 B103	Variable Frequency Vibration: (Test @ Rm)	-	-	-	-	N/A			
CA	G3	MIL-STD-883 Method 2001	Constant Acceleration: (Test @ Rm)	-	-	-	-	N/A			
GFL	G4	MIL-STD-883 Method 1014	Gross and Fine Leak:	-	-	-	-	N/A			
DROP	G5		Drop Test: (Test @ Rm) MEMS cavity parts only. Drop part on each of 6 axes once from a height of 1.2m onto a concrete surface.	-	-	-	-	N/A			
LT	G6	MIL-STD-883 Method 2004	Lid Torque:	-	-	-	-	N/A			
DS	G7	MIL-STD-883 Method 2019	Die Shear:	-	-	-	-	N/A			
IWV	G8	MIL-STD-883 Method 1018	Internal Water Vapor:	-	-	-	-	N/A			

Page 6 of 8 AEC-Q100-REV H-QTR



#### Calculation method of standard failure rate

Target: 0.13um CMOS process product (RL78 series Automobile)

Operating reliability is decided by inherent reliability of device and environment condition of use (See below).

Calculation method of standard failure rate ( $\lambda$ )

$$\lambda = \underline{\lambda b} \times \underline{\pi T}$$
 (FIT)
$$(2)$$
 Temperature parameter
$$(1)$$
 Basic failure rate

(1)Basic failure rate(λb)

 $\lambda b: 0.18 \text{ (FIT)}$ 

(2)Temperature parameter

$$\pi T = \exp \left\{ 11600 \times \text{Ea} \times \left( \frac{1}{273+55} - \frac{1}{273+\text{Ta}} \right) \right\}$$

Ea : Activation energy (eV)
Ta : ambient temperature

πT Simplified chart (Ea=0.7eV)												
Ta(°C)	40	50	55	60	65	70	75	80	85	90	100	110
πТ	0.31	0.68	1	1.45	2.08	2.95	4.15	5.77	7.96	10.88	19.82	34.99

-Confidence level 60% -Standard temperature Ta=55°C

$$MTTF = \frac{1}{\lambda}$$



Product list Report No. MCR-22-0779

	uct list					кер	ort No. MCR-22-07/9
No	Group	Product part number	Package code	No	Group	Product part number	Package code
1	RL78/D1A	R5F10CGBCJFB	PLQP0048KF-A	51			
2	RL78/D1A	R5F10CGBCJXXXFB	PLQP0048KF-A	52			
3	RL78/D1A	R5F10CGBCLFB	PLQP0048KF-A	53			
4	RL78/D1A	R5F10CGBCLXXXFB	PLQP0048KF-A	54			
5	RL78/D1A	R5F10CGCCJFB	PLQP0048KF-A	55			
6	RL78/D1A	R5F10CGCCJXXXFB	PLQP0048KF-A	56			
7	RL78/D1A	R5F10CGCCLFB	PLQP0048KF-A	57			
8	RL78/D1A	R5F10CGCCLXXXFB	PLQP0048KF-A	58			
9	RL78/D1A	R5F10CGDCJFB	PLQP0048KF-A	59			
10	RL78/D1A	R5F10CGDCJXXXFB	PLQP0048KF-A	60			
11	RL78/D1A	R5F10CGDCLFB	PLQP0048KF-A	61			
12	RL78/D1A	R5F10CGDCLXXXFB	PLQP0048KF-A	62			
13	RL78/D1A	R5F10DGCCJFB	PLQP0048KF-A	63			
14	RL78/D1A	R5F10DGCCJXXXFB	PLQP0048KF-A	64			
15	RL78/D1A	R5F10DGCCLFB	PLQP0048KF-A	65			
16	RL78/D1A	R5F10DGCCLXXXFB	PLQP0048KF-A	66			
17	RL78/D1A	R5F10DGDCJFB	PLQP0048KF-A	67			
18	RL78/D1A	R5F10DGDCJXXXFB	PLQP0048KF-A	68			
19	RL78/D1A	R5F10DGDCLFB	PLQP0048KF-A	69			
20	RL78/D1A	R5F10DGDCLXXXFB	PLQP0048KF-A	70			
21	RL78/D1A	R5F10DGECJFB	PLQP0048KF-A	71			
22	RL78/D1A	R5F10DGECJXXXFB	PLQP0048KF-A	72			
23	RL78/D1A	R5F10DGECLFB	PLQP0048KF-A	73			
24	RL78/D1A	R5F10DGECLXXXFB	PLQP0048KF-A	74			
25	1		<b>Q</b>	75			
26				76			
27				77			
28				78			
29				79			
30				80			
31				81			
32				82			
33				83			
34				84			
35				85			
36				86			
37				87			
38	1			88			
39	†			89	†		
40	†			90			
41	†			91			
42	†			92			
43	†			93	†		
44	†			94			
45	+			95	+		
46	+			96	+		
47	+			97	+		
	+	+		98	+		
48 49	+	+		98	+		
50	+			100	+		
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